**Product data sheet** 

## 1. General description

Planar passivated high commutation three quadrant triac in a SOT78D (IITO-220) internally insulated plastic package intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. This "series BT" triac will commutate the full RMS current at the maximum rated junction temperature without the aid of a snubber where "high junction operating temperature capability" is required.

### 2. Features and benefits

- · 3Q technology for improved noise immunity
- · High commutation capability with maximum false trigger immunity
- High immunity to false turn-on by dV/dt
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- · High voltage capability
- · Planar passivated for voltage ruggedness and reliability
- Triggering in three quadrants only
- Internally insulated package
- Isolated mounting base with 2500 V (RMS) isolation

## 3. Applications

- Electronic themostats (heating and cooling)
- · High power motor controls e.g washing machine and vacuum cleaners
- · Rectifier-fed DC inductive loads e.g DC motors and solenoids
- Refrigeration and air conditioning compressors

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit
Absolute	maximum rating			
$V_{DRM}$	repetitive peak off-state voltage		800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{mb} \le 112 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3	16	A
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p$ = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	160	A
		full sine wave; $t_p$ = 16.7 ms; $T_{j(init)}$ = 25 °C	176	Α
T <sub>j</sub>	junction temperature		150	°C

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G + T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	60	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 20 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	-	1.5	V
Dynamic	characteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	1000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	600	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_J$ = 150 °C; $I_{T(RMS)}$ = 16 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; gate open circuit; snubberless condition	15	-	-	A/ms

# 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		T2—T1
2	T2	main terminal 2		G sym051
3	G	gate		symoor
mb	n.c	mounting base; isolated	IITO-220 (SOT78D)	

# 6. Ordering information

**Table 3. Ordering information** 

Type number	Package name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BTA316Y-800BT	IITO-220	BTA316Y-800BTQ	Tube	50	IITO-220E	15-Dec-2017

# 7. Marking

Table 4. Marking codes

uble 4. Marking codes			
Type number	Marking codes		
BTA316Y-800BT	BTA316Y-800BT		

BTA316Y-800BT

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# 8. Limiting values

#### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{mb} \le 112^{\circ}C$ ; <u>Fig. 1</u> ; <u>Fig. 2</u> ; <u>Fig. 3</u>	16	А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p$ = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	160	А
		full sine wave; $t_p$ = 16.7 ms; $T_{j(init)}$ = 25 °C	176	А
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10ms; sine wave	128	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 150mA	100	A/µs
I <sub>GM</sub>	peak gate current		2	А
$P_{GM}$	peak gate power		5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	0.5	W
T <sub>stg</sub>	storage temperature		-40 to 150	°C
T <sub>j</sub>	junction temperature		150	°C

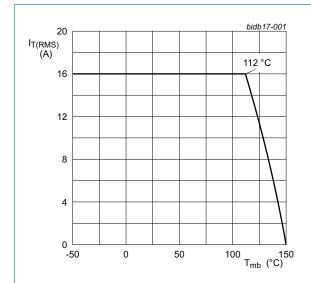


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

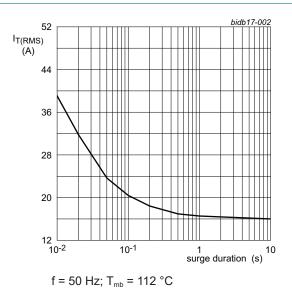


Fig. 2. RMS on-state current as a function of surge duration; maximum values

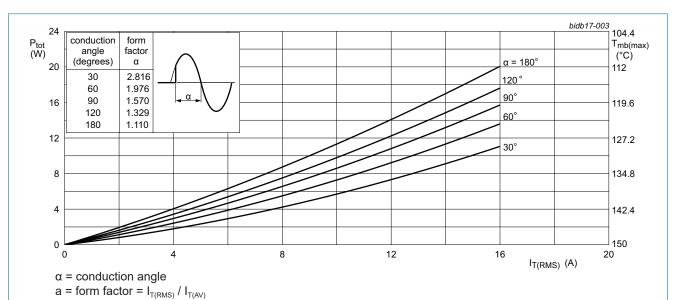


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

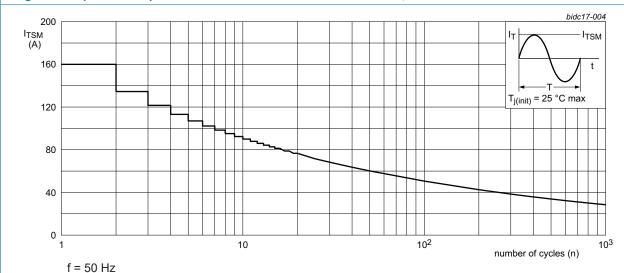
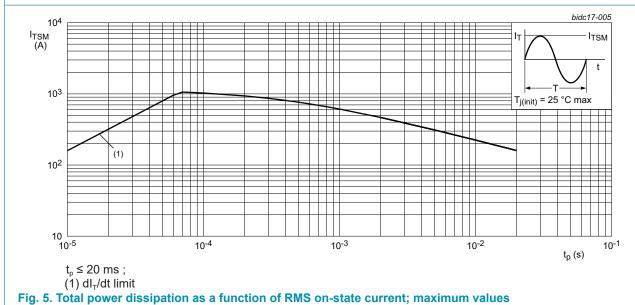


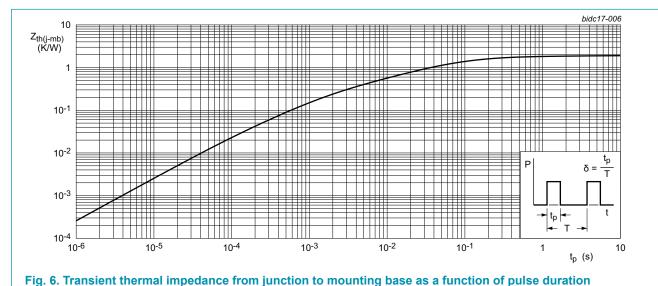
Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



### 9. Thermal characteristics

### **Table 5. Thermal characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 6	-	-	1.9	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient free air	in free air	-	60	-	K/W



rig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

### 10. Isolation characteristics

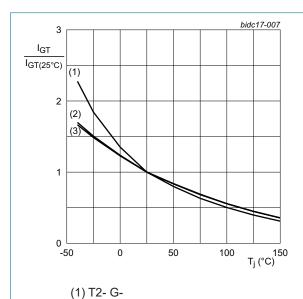
#### **Table 6. Isolation characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>isol(RMS)</sub>	RMS isolation voltage	50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
C <sub>isol</sub>	isolation capacitance	from cathode to external heatsink	-	10	-	PF

## 11. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics		·			'
I <sub>GT</sub> gate trigger current		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
l <sub>L</sub>	latching current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	70	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	80	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	70	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	60	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 20 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	-	1.5	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.8	1	V
		V <sub>D</sub> = 400 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 150 °C; Fig. 11	0.2	0.45	-	V
I <sub>D</sub> off-state current	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C	-	-	5	μA
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	-	2	mA
Dynamic o	haracteristics			'	'	
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	1000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	600	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 16 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; gate open circuit; snubberless condition	15	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 10 \text{ V}/\mu\text{s}; gate open circuit}$	18	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 1 \text{ V}/\mu\text{s}; gate open circuit}$	22	-	-	A/ms



(2) T2+ G-(3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

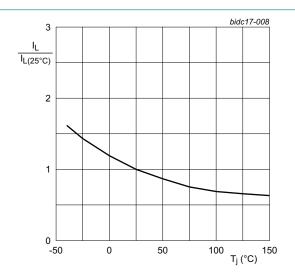


Fig. 8. Normalized latching current as a function of junction temperature

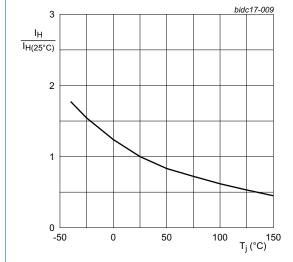
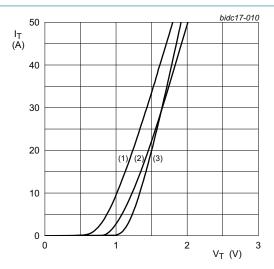


Fig. 9. Normalized holding current as a function of junction temperature



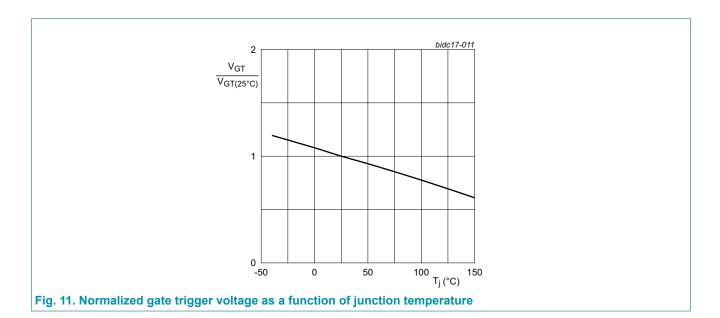
 $V_o = 1.031 \text{ V}; R_s = 0.0203 \Omega$ 

(1) T<sub>i</sub> = 150 °C; typical values

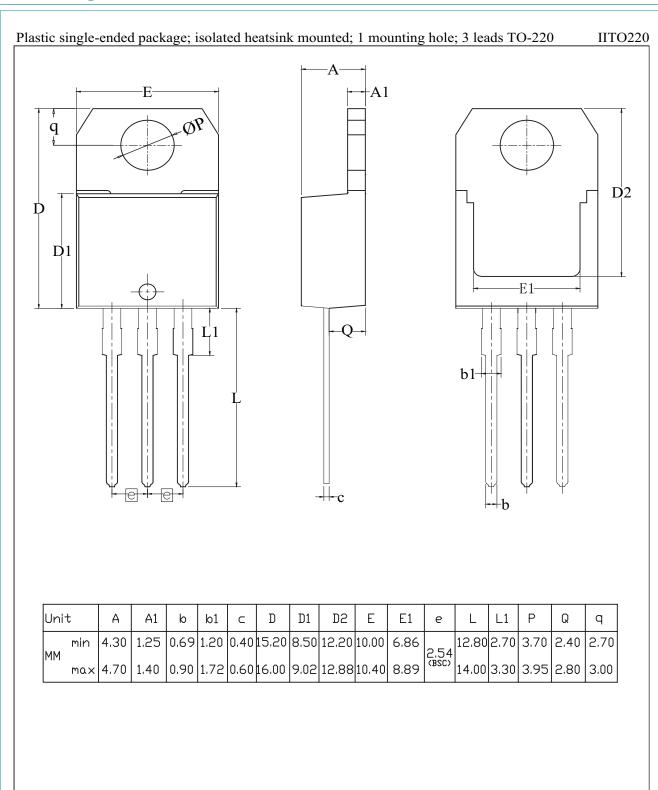
(2) T<sub>j</sub> = 150 °C; maximum values

(3) T<sub>i</sub> = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



# 12. Package outline



## 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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